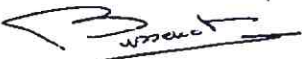


		APPLICATION FOR EXTENSION OF ESCC QUALIFICATION APPROVAL			Page 1
Component Title: Diodes, Microwave, Silicon, Hyper-abrupt junction Tuning Varactor, based on types DH 76XXX		Executive Member: CNES			Date: 21/09/2017
					Appl. No. 273F
Components (including series and families) submitted for Extension of Qualification Approval:					1
ESCC COMPONENT NO.	VARIANTS	RANGE OF COMPONENTS	BASED ON	TEST VEHICLE / S	COMPONENT SIMILAR
5512/023-01-72	01 to 72	Cj(-4V) = 1.0 pF to 15.0 pF	DH 76010 to 150	5512/023-65	All others variants
Component Manufacturer Cobham Microwave		Location of Manufacturing Plant(s) 31, avenue de la Baltique 91978 VILLEBON-SUR-YVETTE Cdex France		Date of original qualification approval: Date: 01/06/2003 Certificate Ref No. 273	
ESCC Specifications used for Maintenance of qualification testing: Generic: 5010 Issue: 2 Detail(s): 5512/023 Issue: 4		Deviations to LVT testing and Detail Specification used: No ☒ Yes ☐ (supply details in Box 15) Deviation from current Specifications: No ☒ Yes ☐ (Supply details)		Qualification Extension Report reference and date: 2017078299-223 A dated 29.08.2017 (See Appendix II)	
Summary of procurement or equivalent test results during current validity period in support of this application (those to ESCC listed first)					8
Project Name	Testing Level	LAT	Date code	Quantity Delivered	
Various			Various	> 2000 (See Appendix I)	
		LAT 2	DC1513	234	
		Chart F4	DC1646	28	
PID changes since start of qualification None ☒ Minor* ☐ Major* ☐ *Provide details in box:		Current PID Verified by: J.L. Roux Ref No: PID 304 Issue: Rev. F Rev Date: 30/06/2015		Name of Executive Representative Date: 21/09/2017	
Current Manufacturing facilities surveyed by: ESA and CNES on 18/12/2007 (Name of Executive Representative) (Date)					11
Satisfactory: Yes ☒ No ☐ Explain					
Report Reference: See box 14					

	APPLICATION FOR EXTENSION OF ESCC QUALIFICATION APPROVAL Component title: Diodes, Microwave, Silicon, Hyper-abrupt junction Tuning Varactor, based on types DH 76XXX Executive Member: CNES Date: 21/09/2017	Page 2 Appl. No. 273F
12 Failure Analysis, DPA, NCCS available: Yes ☐ No ☒ (Supply data) . Ref. No's and purposes:		
13 The undersigned hereby certifies on behalf of the ESCC Executive - that the above information is correct; - that the appropriate documentation has been evaluated; - that full compliance to all ESCC requirements is evidence (except as stated in box 15;) - that the reports and data are available at the ESCC Executive and therefore applies on behalf of CNES as the responsible Executive Member for ESCC qualification status to be extended to the component(s) listed herein. Date: 03/11/2017  J.P. BUSSENOT (Signature of the Executive Coordinator)		
14 Continuation of Boxes above: Box 11 : Audit report QCS/LB/08101 (28/01/2008) and Audit Close-out Report QCS/LB/090302 (31/03/2009). Additional survey conducted on 08.03.2010 in the frame of a NRB on DH76xxx diodes.		

**APPLICATION FOR EXTENSION OF ESCC QUALIFICATION APPROVAL**Component title: Diodes, Microwave, Silicon, Hyper-abrupt junction Tuning Varactor,
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Non compliance to ESCC requirements:

15

No.:	Specification	Paragraph	Non compliance

Additional tasks required to achieve full compliance for ESCC qualification or rationale for acceptability of noncompliance:

16

Executive Manager Disposition

17

Application Approval: Yes ☒ No ☐

Action / Remarks:

Date:

Signature, ESA Representative



APPLICATION FOR EXTENSION OF ESCC QUALIFICATION APPROVAL

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ANNEX 1: LIST OF TESTS DONE TO SUPPORT EXTENSION OF QUALIFICATION

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Tests conducted in compliance with:

- ESCC 5010 generic specification; Chart V (for ESCC/QPL parts);
- Or PID-TFD (for ESCC/QML parts)

Tests vehicle identification/description:

DH 76150 in package M208b (Ceramic Pill B)	

Detail Specification reference: ESCC No 5512 / 023 Issue 4

Chart V	Test	Tick when done	Conditions	Date Code Diffusion Lot	Tested Qty	No. of Rejects	Comments if not performed. Comments on Rejection
Environmental/Mechanical Subgroups	Temperature Cycling	☒	MIL-STD-750 Test Method 1051	1634	6	0	
	Shock Test	☐	MIL-STD-750 Test Method 2016				Not applicable
	Vibration Test	☐	MIL-STD-750 Test Method 2056				Not applicable
	Constant Acceleration	☐	MIL-STD-750 Test Method 2006				Not applicable
	Seal Test	☒	MIL-STD-750 Test Method 1071	1634	6	0	
	Moisture Resistance	☒	MIL-STD-750 Test Method 1021	1634	6	0	
	Seal Test	☒	MIL-STD-750 Test Method 1071	1634	6	0	
	Electrical Measurements at Room Temp.	☒	Table 2 of the Detail Specification	1634	6	0	
	External Visual Inspection	☒	ESCC Basic Specification No. 20500	1634	6	0	
Endurance Subgroup	Operating Life	☒	MIL-STD-750 Test Method 1026	1634	8	0	
	Electrical Measurements during Endur. Test	☒	Table 6 of the Detail Specification	1634	8	0	
	Seal Test	☒	MIL-STD-750 Test Method 1071	1634	8	0	
	External Visual Inspection	☒	ESCC Basic Specification No. 20500	1634	8	0	



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Chart V	Test	Tick when done	Conditions	Date Code Diffusion Lot	Tested Qty	No. of Rejects	Comments if not performed. Comments on Rejection
Assembly Capability Subgroup	Solderability Test	☒	MIL-STD-750 Test Method 2026	1634	2	0	
	Permanence of Marking	☒	ESCC Basic Specification No. 24800	1634	2	0	
	Terminal Strength	☐	MIL-STD-750 Test Method 2036				Not applicable
Additional Tests	Terminal Impedance Test	☒	MIL-STD-750 Test Method 3101	1634	6	0	
	Forward Voltage Test	☒	MIL-STD-750 Test Method 4011	1634	6	0	

